## The 21<sup>st</sup> Korean Conference on Semiconductors 제21회 한국반도체학술대회

February 24–26, 2014 / Hanyang University, Seoul, Korea

A. Interconnect & Package 분과

## [TC2-A] Plating and Reliability

Date	Feb. 25, 2014 (Tue.)	
Place	Room C / 제1공학관 401호 (# 401, Engineering Building I)	
		Session Chair: 김수현 교수(영남대학교),
TC2-A-1	11:10-11:25	<b>Cu Electrodeposition on Ru Seed Layer Prepared by Atomic Layer</b> <b>Deposition</b> 저자: Seunghoe Choe <sup>1</sup> , Myung Jun Kim <sup>1</sup> , Hyun Seok Ko <sup>2</sup> , Young Kwang Kim <sup>3</sup> , O Joong Kwon <sup>3</sup> , and Jae Jeong Kim <sup>1</sup> 소속: <sup>1</sup> School of Chemical and Biological Engineering, Seoul National University, <sup>2</sup> Department of Material Science and Engineering, Incheon National University, <sup>3</sup> Department of Energy and Chemical Engineering, Incheon National University
TC2-A-2	11:25-11:40	<b>Cu-Ag Superfilling for Damascene Metallization</b> 저자: Myung Jun Kim <sup>1</sup> , Taeho Lim <sup>1</sup> , Kyung Ju Park <sup>1</sup> , Oh Joong Kwon <sup>2</sup> , and Jae Jeong Kim <sup>1</sup> 소속: <sup>1</sup> School of Chemical and Biological Engineering, Seoul National University, <sup>2</sup> Department of Energy and Chemical Engineering, Incheon National University
TC2-A-3	11:40-11:55	Real-Time Observation of Cu Electroless Deposition: Synergetic Suppression Effect of 2,2'-Dipyridyl and 3-N,N- Dimethylaminodithiocarbamoyl-1-propanesulfonic Acid 저자: Taeho Lim, Myung Jun Kim, Kyung Ju Park, Kwang Hwan Kim, and Jae Jeong Kim 소속: School of Chemical and Biological Engineering, Seoul National University
TC2-A-4	11:55-12:10	Effect of Pulsed Electric Field on Dielectric Breakdown in Damascene Cu Interconnects 저자: Han-Wool Yeon <sup>1</sup> , Jun-Young Song <sup>1</sup> , Jang-Yong Bae <sup>2</sup> , Yu-Chul Hwang <sup>2</sup> , and Young-Chang Joo <sup>1</sup> 소속: <sup>1</sup> Department of Materials Science & Engineering, Seoul National University, <sup>2</sup> Memory Division, Samsung Electronics Co Ltd.
TC2-A-5	12:10-12:25	Flexible Cu Barrier of PAH/PSS Laminar Structures using Layer-by-Layer (LbL) Method 저자: Daekyun Jeong, Chiyoung Lee, and Jaegab Lee 소속: Department of Advanced Materials Engineering, Kookmin University